Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/665,312	STUPLE ET AL.	
Examiner	Art Unit	
Quoc A. Tran	2176	

SEARCHED				
Class	Subclass	Date	Examiner	
715	530	% 14/2006	(A)	
715	532	% 14/2006	B	
715	516	15/4/2006	3	
715	517	3 4/2006	D	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	<u> </u>		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
INVENTORS SEARCH CHECK FOR DOUBLE PATENT	<i>7</i> 8/4/2006	D
EAST (US-PAT, US-PGPUB,) See Search Histoty Printout	<i>J</i> er4/2006	8
ACM Digital Librarysee Search History Printout	B4 /2006	3